• Common JK Gate Input

logic

FUNCTION TABLE

INF	UT A1	t _n	OUTPUT AT tn+1					
JK	Лţ	Κ [†]	a	la				
L‡	Х	Х	Q _n	ā				
Н	L‡	L‡	Q _n	\overline{a}_n				
] н	L	Н	L	н				
н	н	L	н	L				
Н	н	н	ā _n	a _n				

t SN54104/SN74104J = J1 · J2 · J3. $K = K1 \cdot K2 \cdot K3$ $SN54105/SN74105J = J1 \cdot J2 \cdot J3$.

 $K = K1 \cdot \overline{K2} \cdot K3$ ‡ These low-levels must be maintained while the clock is low.

NOTES:

A. t_n = bit time before clock pulse

- bit time after clock pulse

B. t_{n+1} = bit time after clock pulse C. H = high, L = low, X = irrelevant

SN54104 . . . J OR W PACKAGE SN74104 . . . J OR N PACKAGE

TYPES SN54104, SN54105, SN74104, SN74105

	TT-5
JK□1	U14DVcc
PRE 2	13 CLR
K1 □3	12 J3
J1 □4	11 □ K3
J2 🗖 5	10∐ K2
0 □6	9∐ CLK
GND 🗖 7	8 □ 0

SN54105 . . . J OR W PACKAGE SN74105 . . . J OR N PACKAGE

лкДі	U14D VCC
PRE 2	13 CLR
K1 □3	12 J3
J1 □4	11 □ K3
<u>J2</u>	10 K2
0 Д6	9 ☐ CLK
GND []7	8∫_⊡

description

These J-K master-slave flip-flops feature a buffered clock input, direct preset and clear, gated J and K inputs, and a common JK input. The clock buffer offers typical TTL high noise immunity, low clock-line loading, and, in most cases, eliminates the need for stringent control of system-clock rise and fall times. When activated, the direct preset and clear inputs control the state of both the master and slave flip-flops independent of the clock and synchronous-input states. Gated inputs may be used to perform a wide variety of control functions without the need for external gates, and the common JK input simplifies hardware design for applications utilizing a single gate-control source.

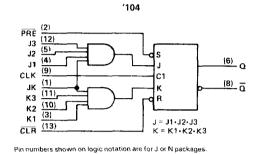
Due to the internal clock buffer, the JK input gates accept data when the clock line is low, and transfer of data from the master to the slave occurs during the clock-line transition from the low state to the high state. When the clock line is high, the data inputs are inhibited.

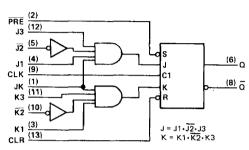
The SN54104/SN74104 includes internal capacitive loading on the J and K input gates and, as the input setup and hold times are lengthened, this circuit displays improved performance in systems where appreciable clock skew is anticipated.

The SN54105/SN74105 offers an inverting data input to each of the J and K input gates for additional control flexibility. As the input setup and hold times are not lengthened, this circuit permits operation at higher toggle rates than the SN54104/SN74104.

These TTL circuits feature one-volt typical d-c noise margins and are compatible for use with most TTL families. Full fan-out to 10 normalized Series 54/74 loads is available from the outputs. The SN54104 and SN54105 circuits are characterized for operation over the full military temperature range of -55°C to 125°C, and the SN74104 and SN74105 circuits are characterized for operation from 0°C to 70°C.

logic diagrams





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (See Note 1)		
Input voltage		5.5 V
Voltage applied to any output (See N	ote 2)	5.5 V
Operating free-air temperature range:	SN54104, SN54105 Circuits	55°C to 125°C
	SN74104, SN74105 Circuits	
Storage temperature range		65°C to 150°C

recommended operating conditions

TTL DEVICES

				SN54'		SN74'			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage (see Note 1)			5	5.5	4.75	5	5.25	V
VIH	High-level input voltage		2		-	2			V
VIL	Low-level input voltage				0.8			8.0	V
ЮН	High-level output current				- 1			- 1	mA
lOL	Low-level output current				16			16	mA
	Pulse duration	CLK Low-level	151			15 [†]			
tw		PRE and CLR	20 [†]			20 [†]	_		ns
	Setup time for high-level data	′104	35			35 [†]			
tsu	(See Note 4)	105	10 [†]			10 [†]			ns
	Release time for low-level data	′104			10 [†]			10 [†]	
t _r	(See Note 3)	′105			1 [†]			1†	ns
TA	Operating free-air temperature		- 55		125	0		70	°C

- † These conditions are recommended at V_{CC} = 5 V, T_A = 25°C.

 NOTES: 1. Voltage values are with respect to network ground terminal.

 2. This rating applied at the Q output with preset held low and at the Q output with clear held low.

 3. Refease time for low-level data is an interval between the release of low-level data and the positive-going edge of the clock pulse; this interval being sufficiently short to ensure recognition of the low-level data.

 4. Setup time for high-level data is an interval between the arrival of the high-level data and the positive-going edge of the clock pulse; this interval being sufficiently long to ensure recognition of the high-level data.

PAR	AMETER		TEST CONDITIONS†	•	MIN	TYP‡	MAX	UNIT
VOH		V _{CC} = MIN,	IOH = - 1 mA		2.4	2.7		V
VOL		V _{CC} = MIN,	I _{OL} = 16 mA		Ī	0.2	0.4	V
	PRE or CLR					8	120	
ЧΗ	J or K	V _{CC} = MAX,	V _I = 4.5 V			4	80	μА
	All other	Ì				2	40	
	PRE or CLR	V _{CC} = MAX,	V ₁ = 0.4 V			– 3	– 4.75	
'1L F	J or K					– 2.2	- 3.2	mA
	All other					- 1.1	- 1.6	
¹cc -	'104	V = 5 V				15	24	mA
	105	V _{CC} = 5 V				17	28	MA

[†] For conditions shown as MIN or MAX, use appropriate value specified under recommended operating conditions for the applicable device

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 5)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN TYP	MAX	UNIT
tPLH	01.6	Q or $\overline{\Omega}$	R ₁ = 400 Ω, C ₁ = 15 pF	9	15	ns
tpui	CLK Q or Q	R _L = 400 Ω, C _L = 15 pF	16	25	""	

NOTE 5: See General Information Section for load circuits and voltage waveforms.

type. ‡ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{C}$.